

# Search Notes



Application/Control No.

10/649,671

Examiner

Hong C. Kim

Applicant(s)/Patent under  
Reexamination

HIRAIWA ET AL.

Art Unit

2186

## SEARCHED

Class	Subclass	Date	Examiner
711	112 170 173	8/15/05	rdh
	203		
	4 6		
713	100		
709	226		
714	007		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST	8/15/05	rdh